Multiple Instrument Station Module

Digital Storage Oscilloscope

Vertical

Channels 2 + external trigger
Sampling rate 50MS/s (5GS/s ERS mode)

Bandwidth > 100MHz
Coupling AC, DC, GND
Input impedance 1M Ohm, 25pF

Vertical sensitivity 20mV to 2V per division

Vertical resolution 8 bits Max. input voltage 100VDC

Horizontal

Sweep speed 5ns/div to 5s/div
Memory 64kbytes/channel
Modes normal, auto, single

Internal trigger

Source channel 1, channel 2, function generator

Slope positive, negative Sensitivity < 0.5 divisions

Coupling AC, DC, HF reject, LF reject

External trigger

Input impedance 1M Ohm, 25pF Slope positive, negative

Sensitivity < 10mV

Coupling AC, DC, HF reject, LF reject

Max. input voltage 100V DC

Trigger delay

Pre-trigger 0 to 100% of sweep time Post-trigger 0 to 100% of sweep time

Measurements

Automatic standard waveform parameters

Comparison time and voltage

Function Generator

Waveforms sine, square, triangle, single-shot pulse Frequency range 0.1Hz to 10MHz, resolution 0.1% of range full

scale

Pulse width 100ns to 10s Modulation modes AM, FM, PWM Modulation frequency 400Hz internal

Duty cycle 20% to 80%, resolution 1%
Amplitude 0V to 5V, resolution 50mV
DC offset -7.5V to 7.5V, resolution 50mV

Rise/fall time 25ns
Output impedance 50 Ohm

Sweep mode

Start frequency 0.1Hz to 10MHz
End frequency 0.1Hz to 10MHz
Steps 1 to 1000
Time per step 0.1s to 9.9s

Digital Floating Multimeter

Channels 2 channels 10M Ohm

Statistics minimum, maximum, average

Channel 1

Modes

Voltage range

DC volts, AC volts

0 to 400V

0.005% full scale

+/-0.05%

AC voltage resolution

AC voltage resolution

AC voltage accuracy

AC voltage accuracy

+/-0.1%

to voltage accuracy +/-0.19

Channel 2

Modes DC volts, AC volts, DC current, AC current,

resistance

0 to 400V Voltage range Current range 0 to 2A Resistance range 0 to 20M Ohm DC voltage resolution 0.005% full scale DC voltage accuracy +/-0.05% AC voltage resolution 0.05% full scale AC voltage accuracy +/-0.1% DC current resolution 1mA +/-0.1% DC current accuracy AC current resolution 1mA

AC current accuracy +/-0.2%
Resistance resolution 0.01% full scale

Resistance accuracy +/-0.1%

Auxiliary Power Supply

Output Voltages +5V, +9V, -9V
Output Current +5V supply - 500mA

+9V supply - 100mA -9V supply - 100mA



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Multiple Instrument Station (continued)

Frequency Counter

Modes event, frequency, pulse width

Channel 1

Impedance 50 Ohm

Frequency range 1MHz to 150MHz

Sensitivity < 5mV rms @ 2MHz to 10MHz

<15mV rms @ 10MHz to 100MHz

Pulse response 50mV, 25ns pulse @ 500Hz

Maximum input +/- 5V

Basic accuracy +/- 0.02% +/- 1 count

Channel 2

Impedance 1 MOhm
Frequency range 2Hz to 100MHz
Sensitivity < 300mV rms @ 10Hz

< 150mV rms @ 10kHz to 10MHz

< 350mV rms @ 33MHz

Maximum input 200V rms

Basic accuracy +/- 0.02% +/- 1 count

Event Mode

Ch1 event count 0 to 9,999,999,999 Ext gate width 0 to 9,999,999 minimum 20ns

Ext gate width time 6 hours, 10ms resolution

10.74s, 5µs resolution 84ms, 40ns resolution

Statistics lowest, highest, average Display frequency, period, RPM events,

pulse width, gate time

Universal I/O

Number of channels 4 channels

Analogue Channels

Modes voltage output, voltage input, current output,

current input

Voltage output range
-9V to +9Vm resolution 10mV
Voltage input range
-10V to +10V, resolution 10mV
Current output range
0 to +/-20mA, resolution μA

Digital Channels

Modes logic output high, logic output low

logic measurement

Voltage TTL compatible logic levels

Accessories
Output voltages

2 x DSO probes

1 x yellow probe and cable 1x blue probe and cable 1x black probe and cable

1x universal I/O cable (not terminated)

Options

Internal fitting PCI Interface

External fitting - MultiLink case (cost option) with USB

- External case (cost option) which will hold up

to 5 System8 modules (USB interface).

PC Requirements Pentium (1GHz) System

Windows XP™

20MB of free hard disk space

256 MB RAM CD ROM Drive

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24 channel Analogue IC Tester Module

V-I test capability

Number of test channels: 24 + 2 probes and references 2 V to 50 V peak to peak Test voltage:

Voltage resolution: 8 to 12 bits 37.5 Hz to 12 kHz Test frequency: Test current: 1 µA to 150 mA Source impedance: 100 Ohm to 1 M

Sine, square, triangle, ramp, pulse Test waveforms:

Waveform modes: V-I, V-T, I-T

Multi-plot with single waveform zoom Waveform display: Automatic comparison algorithm for good Waveform comparison: and bad boards using live probes or disk

V-I comparison tolerance: 50 mV to 500 mV with 50 mV resolution Package support: DIL. SOIC. PLCC. QFP and variants with

MultiProbes

Pulse output: Positive, negative or bipolar for thyristors/

triacs

Pulse amplitude: Adjustable to +/-10 V Can be calibrated by user Calibration:

Analogue functional test capability

Number of I/O channels: 24 independent + 3 special discrete

channels

-12 V to +12 V Driver voltage:

Driver voltage resolution: 10 bit

Driver output current: 200 mA max sink or source Driver states: Voltage source, current source, off

Discrete source current: 10 µA - 150 mA. (driving a load returned to 0

Driver source impedance: 34 Ohm (34 Ohm, 1 k or 10 k on discrete

channels)

Sensor input voltage: +/-24 V Sensor voltage protection: +/-50 V Sensor input impedance: 2 M Sensor voltage resolution: 12 bit Restrict voltage: -10 V to +10 V

Restrict voltage resolution: 8 bit

Sensor current measurement: 1 mA to 150 mA (10 nA to 150 mA on discrete

channels)

Sensor current resolution: 12 bit

Sensor current input impedance: 50 Ohm (50 Ohm, 1 k, 10 k or 1 M

on discrete channels)

Short detection threshold: <4 Ohm Link detection threshold: <10 Ohm

Test modes: Single, unconditional loop, pass loop, fail

Test clip positioning: Automatically adjusts for clip orientation Automatically modifies test for IC/PCB Circuit compensation:

connections

Test waveforms and voltages displayed Test trace: Test analysis: Displays test parameters such as gain, hfe,

feedback

IC test capability: Op-amps, comparators, DACs, ADCs,

switches and special function analogue ICs

in-circuit.

Discrete test capability: Transistors, FETs, thyristors, triacs in- or

out-of-circuit

IC test libraries: Analogue, discrete, package, user

Result comparison: Results can be saved for good/bad board

comparison

Package support: DIL, SOIC, PLCC and variants with

MultiProbe kits

Structured programming language for SLIM test programming:

library additions

Other specifications

Electrical input: (typical) +12 V, 1 A (max)

(typical) -5 V, 750 mA (typical) -12 V, 100 mA 147 x 202 x 42 mm

Dimensions:

Weight: 1 kg

Accessories

Standard 1 x SMD test tweezer set and adapters

> 1 x 24 way test clip and cable assembly 1 x Blue V-I probes and adapter 1 x Yellow V-I probes and adapter

2 x Pulse leads 2x Ground leads 3 x Discrete leads

Options

Internal fitting **PCI** interface

External fitting MultiLink case (cost option) with USB.

> External case (cost option) which can hold up to 5 SYSTEM 8 modules (USB interface).

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64 channel Board Fault Locator Module

Digital IC test capability

Number of I/O channels: 64-256 Number of guard outputs: 4 or 8

64 x 2, 128 x 2 with additional modules Live comparison:

Drive output voltage: TTL/CMOS compatible Drive output current: Device dependent Typical H-L80mA@0.6V

Typical L-H 200mA@2V Max. 400mA

Drive slew rate: >100V/us Receive input: +/-10V Input impedance:

Programmable for tri-state/open collector Termination:

Drive states: Low, high, tri-state Over voltage protection: <0.5V.>5.5V Test time: Dependent on device

In-circuit. Out-of-circuit (with adapter) Circuit modes:

Power supply for board under test

Automatic power supply: 1x5V@5Afixed

(2x5V@5A fixed for 128 channels)

Over voltage protection: 7V Short circuit current: 7A

Test modes

Single: Single test

Unconditional, loop while good, loop while bad Loop:

Find tightest valid thresholds Auto:

Test thresholds

Resolution: 100mV

TTL 0.1V to 1.1V Low levels:

CMOS 0.1V to 1.5V

Switching levels: TTL 1.0V to 2.3V

CMOS 1.0V to 3.0V

High levels: TTL 1.9V to 4.9V CMOS 1.9V to 4.9V

TTL 0.1V to 1.1V

Swept low levels:

CMOS 0.1V to 1.5V

Swept switching levels: **TTL 1.2V**

CMOS 2.5V

Swept high levels: TTL 1.9V to 4.9V

CMOS 1.9V to 4.9V

Test types

Truth table (functional): Library based functional test Connections (MDA): Short circuit detection

> Floating input detection Open circuit detection Linked pin detection

Voltage: Resolution 10mV

Range +/-10V

Logic state detection VI: Number of channels 64 - 256

Sweep ranges -10V to +10V

(programmable)

Maximum test current 1mA

Multi-plot with single waveform zoom

Thermal: Indication of pin temperature

Test libraries

Library classes: TTL 54/74 logic, CMOS, Memory, Interface, LSI,

Microprocessor, PAL/EPLD, Linear, Package,

Special and user defined

DIL, SOIC, PLCC, QFP Package types:

Accessories

Standard Automatic out-of-circuit adapter

> 1 x 64 way test cable 1 x 64 way split test cable 1 x V-I probe assembly 1xBDO cable

1 x Short locator cable 1 x Ground clip 1xPSU lead set

Options

Internal fitting **PCI** interface

MultiLink case (cost option) with USB. External fitting

External case (cost option) which can hold up to

5 SYSTEM 8 modules (USB Interface).

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Variable Power Supply Module

Logic Supply

Low voltage output for digital circuits

Voltage 2.5V to 6V programmable

Resolution 0.01V

Over voltage 3V to 7V programmable threshold

Resolution 0.1V
Current 5A
Short circuit current 7A

Short circuit duration indefinite (auto recovery)
Load regulation 0.5% (20% to 80% load change)

Ripple voltage 80mV pk-pk max

Variable Positive Supply

Positive voltage output for analogue circuits

Voltage 0 to +24V programmable

Resolution 0.01V Current 1.5A max

Over current limit 50mA to 1.5A programmable threshold

Short circuit current 1.5A

Short circuit duration indefinite (auto recovery)
Load regulation 0.1% (20% to 80% load change)

Ripple voltage 50mV pk-pk max

Variable Negative Supply

Negative voltage output for analogue circuits

Voltage 0 to -24V programmable

Resolution 0.01V Current 1.5A max

Over current limit 50mA to 1.5A programmable threshold

Short circuit current 1.5A

Short circuit duration indefinite (auto recovery)
Load regulation 0.1% (20% to 80% load change)

Ripple voltage 50mV pk-pk max

Physical data

Weight 5kg

Size 295 x 247 x 65mm Power rating 150W max

Connectors and cables power cable, parallel interface cable, logic

and ground cables, +V and -V cables

PC requirements (Minimum) System capable of running

Windows 95/98 with at least 32MB of RAM

and 20MB of free hard disk space

ECP/EPP capable parallel port or 16550

serial port

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24 channel Analogue Test Station Module

V-I test capability

Number of test channels: 24 + 2 probes and references
Test voltage: 2 V to 50 V peak to peak

Test waveforms: Sine, square, triangle, ramp, pulse

Waveform modes: V-I, V-T, I-T

Waveform display: Multi-plot with single waveform zoom
Waveform comparison: Automatic comparison algorithm for good and bad boards using live probes or saved

data

V-I comparison tolerance: 50 mV to 500 mV with 50 mV resolution Package support: 50 mV to 500 mV with 50 mV resolution DIL, SOIC, PLCC, QFP and variants with

MultiProbes

Pulse output: Positive, negative or bipolar for thyristors/

triacs

Pulse amplitude: Adjustable to +/-10 V

Calibration: Automatic

Accessories

Standard 1 x 24 way test cable

2 x Ground leads 2 x Pulse leads

1 x Blue V-I probe and adapter 1 x Yellow V-I probe and adapter 1 x SMD test tweezer set

Options

Internal fitting PCI interface

External fitting MultiLink case (cost option) with USB.

External case (cost option) which can hold up to 5 SYSTEM 8 modules (USB

Interface).

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Training Board

Board Fault Locator Functions

Digital Test: Test types

CCT conditions
Loop testing
Logic trace
Thresholds
Digital V-I
Invalid conditions

Grounding issues
Tri-state testing
Open collector testing

Guarding

Comparison tolerance

Live comparison

Graphical Test Generator: Configuring the graphical test generator

Setting the thresholds Inputting waveforms Defining responses Auto-learning responses Equivalent Functions

IC identifier Equivalent Functions
Use of thresholds

Short locator: Operation

Ranges

EPROM verifier: Loading and saving EPROM files

Effect of bus shorts Use of BDO signals

Analogue Test Station Functions

Analog V-I: Effect of varying voltage and impedance

Effect of varying waveform

Difference between VI, VT and IT tests

Dual probe mode Storing test result Comparison tolerance

Clip testing MultiProbe testing Probe compensation

Matrix VI

Use of pulse output Testing Relays

AICT Functions

Analogue functional test: Test types

Device conditions Supply range Test analysis box Loop testing Analogue trace

Generic type versus part number

Discrete Testing: Use of special channels

Measuring gain and voltage Effect of parallel components

Multiple Instrument Station Functions

Function generator: Low frequency waveforms

Higher frequency with duty cycle

Changing wave shape, amplitude and offset

Use of single pulse mode Effect of phase lock Effect of modulation Sweep mode

Frequency counter: Measuring frequency/period

Using event mode

Setting target values

Changing tolerances and display ranges

Calculator

DSO Use of controls

Acquisition modes Aliasing

ERS mode

Automatic measurements
Waveform storing and comparison
Adjusting comparison tolerances

Multimeter LM324 circuit

Calculating op amp gain and DAC values

Logging data

MIS Power Supply Simple operation

MIS Universal I/O Simple discrete circuit (diode, transistor)

Analogue output voltage and current Measuring voltage and current Testing transistors and diodes

Electronic Principles Covered

Ohms Law R/L/C Circuits Diode Operation Transistor Operation MOSFET and FET Operation

Op Amp Operation Comparator Operation

Other specifications

Electrical input: Powered by MIS power supply or via

external 6-way Molex through-hole

connector.

(typical) 5V, 600 mA (max) (typical) +12V 100 mA (typical) -12 V, 100 mA 209 x 165 x 19 mm

Dimensions: 209 x 169

Weight: 222g

Accessories

Standard 1 x power connector

1 x SYSTEM 8 Premier test flow files and

manual

Options

Cables: 3 x BNC cables for MIS

10-way cable for MIS

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